SQ3000[™]3D CMM

The Ultimate in Speed and Accuracy for Semiconductor Applications







Fastest – Seconds, not Hours

- Significantly speeds attaining coordinate measurements vs. traditional CMMs
- Reduces engineering resource time



Easy-to-use Interface

- Simplifies process with award-winning, intuitive, touch screen experience
- Quick programming for complex applications
- Multi-process capable AOI, SPI, AOM, CMM



Metrology-grade Accuracy

- Achieve metrology-grade accuracy with MRS-enabled technology
- Repeatable and reproducible measurements for SMT, Semiconductor, Microelectronics and Metrology Applications



$\mathbf{SQ3000}^{\mathsf{T}}$ The Ultimate in Speed and Accuracy

High Precision Accuracy with Multi-Reflection Suppression® (MRS®) Sensor Technology

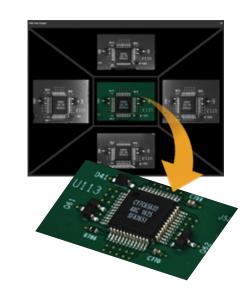
The SQ3000 is powered by CyberOptics' breakthrough 3D sensing technology comprising four multi-view 3D sensors and a parallel projector delivering metrology grade accuracy at production speed. CyberOptics' unique sensor architecture simultaneously captures and transmits multiple images in parallel while proprietary 3D fusing algorithms merge the images together. The result is ultra-high quality 3D images and high-speed inspection.

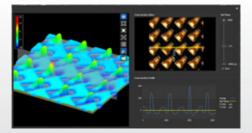


Multi-Reflection Suppression (MRS) Technology

SQ3000 offers unmatched accuracy with the revolutionary MRS technology by meticulously identifying and rejecting reflections caused by shiny components. Effective suppression of multiple reflections is critical for accurate measurement making MRS an ideal technology solution for a wide range of applications including those with very high quality requirements.

CyberOptics has advanced the proprietary Multi-Reflection Suppression (MRS) sensor to an even finer resolution. The Ultra-High Resolution MRS sensor enhances the SQ3000 3D CMM platform, delivering superior inspection performance for socket metrology, advanced packaging, solder ball & bump, micro-electronics, and a variety of semiconductor applications where an even greater degree of accuracy and inspection reliability is critical.









Packaging SMT



Solder Ball and Bump

Large Board Capability

SQ3000 X^{m} supports large boards up to 710 x 610 mm, and is capable of inspecting the most demanding assemblies at production speed without compromising on measurement accuracy and repeatability.



Intuitive, Easy-to-Use Software

The multi-award winning SQ3000 AOI software is a more powerful yet extremely simple software designed with an intuitive interface. Including multi-touch controls, 3D image visualization tools and ultra-fast programming capabilities that brings ease-of-use to a completely new level, which reduces training efforts and minimizes operator interaction - saving time and cost.



Enable Smarter, Faster Inspection

Reduce time to program and tune with ultra-fast programming capabilities including auto tuning and enhancements that significantly speed setup, simplify the process, reduce training efforts and minimize operator interaction. Al² (Autonomous Image Interpretation) technology is all about keeping it simple - no parameters to adjust or algorithms to tune. And, you don't need to anticipate defects or pre-define variance either - Al² does it all for you. With Al², you have the power to inspect the most comprehensive list of features and identify the widest variety of defects. Al² offers precise discrimination with just one panel inspection making it a perfect solution for high-mix and high-volume applications.

Seconds, not Hours - Faster, Highly Accurate Coordinate Measurement Suite (CMM)

CyberCMM™, a comprehensive software suite of coordinate measurement tools provides highly accurate, 100% metrology-grade measurement on all critical points much faster than a traditional CMM, including coplanarity, distance, height and datum X, Y to name a few. A fast and easy set-up can be performed in less than an hour for programming complex applications as compared to slow, engineering resource-intensive set-up that typically requires multiple adjustments with traditional coordinate measurement machines (CMMs)

Fast, Scalable SPC Solution

CyberReport™ offers full-fledged machine-level to factory-level SPC capability with powerful historical analysis and reporting tools delivering complete traceability for process verification and yield improvement. CyberReport™ is easy to setup and simple to use while providing fast charting with a compact database size.





Inspection Capabilities	Standard MRS Sensor	High-Speed MRS Sensor	High-Resolution MRS Sensor	Ultra-High Resolutior MRS Sensor
Inspection Speed	40 cm ² /sec (2D+3D)	50 cm ² /sec (2D+3D)	20 cm ² /sec (2D+3D)	15 cm ² /sec (2D+3D)
XY Resolution	10 μm		7 μm	
Z Resolution	0.5 μm			
Minimum Feature Size	100 μm		70 μm	
Maximum Feature Size	SQ3000: 510 x 510 mm (20 x 20 in.), SQ3000-X: 710 x 610 mm (27.9 x 24 in.))	
Minimum Feature Height	50 μm			
Maximum Feature Height	24 mm		8 mm	
XY R&R	< 3 µm 1 sigma		< 2 µm 1 sigma	
Z R&R	< 2 µm 1 sigma			
Accuracy XY	6 μm		5 μm	
Accuracy Z	2 µm			
Height Clearance	Top: 50 mm ; Bottom: 30mm			
Carrier Thickness	0.3 - 5 mm (10 mm Option)			
Coordinate Measurement		3	ession Shifted, Datum X,Y	
Coordinate Measurement Capability	Offset / Value / Locatio Distance to plane / 2nd Plus / Minus / Multiple	n / List of X,Y Values, Heig	ession Shifted, Datum X,Y ht / Local Height / Regress / Absolute / 2sqrt / VC, Ma	ion / Radius, Coplanarity/
Coordinate Measurement Capability Vision System & Technology	Offset / Value / Locatio Distance to plane / 2nd Plus / Minus / Multiple	n / List of X,Y Values, Heig	ht / Local Height / Regress	ion / Radius, Coplanarity/
Coordinate Measurement Capability Vision System & Technology Imagers	Offset / Value / Locatio Distance to plane / 2nd Plus / Minus / Multiple Multi-3D sensors	n / List of X,Y Values, Heig	ht / Local Height / Regress / Absolute / 2sqrt / VC, Ma	ion / Radius, Coplanarity/
Coordinate Measurement Capability Vision System & Technology Imagers Resolution	Offset / Value / Locatio Distance to plane / 2nd Plus / Minus / Multiple	n / List of X,Y Values, Heig	ht / Local Height / Regress	ion / Radius, Coplanarity/ ax / Min / Ave / Sigma /
Coordinate Measurement Capability Vision System & Technology Imagers Resolution Field of View (FOV)	Offset / Value / Locatio Distance to plane / 2nd Plus / Minus / Multiple Multi-3D sensors Sub 10 µm 36 x 30 mm	n / List of X,Y Values, Heig d Order fitting, Difference	ht / Local Height / Regress / Absolute / 2sqrt / VC, Ma 7 µm 26 x 26 mm	ion / Radius, Coplanarity/ ax / Min / Ave / Sigma /
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Coordinate Measurement Capability Vision System & Technology Imagers Resolution Field of View (FOV) Image Processing Programming Time CAD Import System Specifications Machine Interface	Offset / Value / Locatio Distance to plane / 2nd Plus / Minus / Multiple Multi-3D sensors Sub 10 µm 36 x 30 mm Autonomous Image In <13 minutes (for estab Any column-separated preparation SMEMA, RS232 and Eth	n / List of X,Y Values, Heig d Order fitting, Difference 36 x 36 mm terpretation (AI ²) Technolo lished libraries) text file with ref designat	ht / Local Height / Regress / Absolute / 2sqrt / VC, Ma 7 µm 26 x 26 mm ogy, Coplanarity and Lead or, XY, Angle, Part no info;	ion / Radius, Coplanarity/ ax / Min / Ave / Sigma / 21 x 21 mm Measurement
Coordinate Measurement Capability Vision System & Technology Imagers Resolution Field of View (FOV)	Offset / Value / Locatio Distance to plane / 2nd Plus / Minus / Multiple Multi-3D sensors Sub 10 µm 36 x 30 mm Autonomous Image In <13 minutes (for estab Any column-separated preparation SMEMA, RS232 and Eth 100-120 VAC or 220-24	n / List of X,Y Values, Height Order fitting, Difference described as 36 x 36 mm described libraries) I text file with ref designate mernet	ht / Local Height / Regress / Absolute / 2sqrt / VC, Ma 7 µm 26 x 26 mm ogy, Coplanarity and Lead or, XY, Angle, Part no info;	ion / Radius, Coplanarity/ ax / Min / Ave / Sigma / 21 x 21 mm Measurement
Coordinate Measurement Capability Vision System & Technology Imagers Resolution Field of View (FOV) Image Processing Programming Time CAD Import System Specifications Machine Interface Power Requirements Compressed Air	Offset / Value / Locatio Distance to plane / 2nd Plus / Minus / Multiple Multi-3D sensors Sub 10 µm 36 x 30 mm Autonomous Image In <13 minutes (for estab Any column-separated preparation SMEMA, RS232 and Eth 100-120 VAC or 220-24	n / List of X,Y Values, Height Order fitting, Difference di Order fitting,	ht / Local Height / Regress / Absolute / 2sqrt / VC, Ma 7 µm 26 x 26 mm ogy, Coplanarity and Lead or, XY, Angle, Part no info;	ion / Radius, Coplanarity/ ax / Min / Ave / Sigma / 21 x 21 mm Measurement

Options

Barcode Reader, Rework station, SPC Software, Alignment Target

SQ3000[™] D (Dual Lane), and SQ3000[™] DD (Dual Lane - Dual Sensor) models available



